## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10055457	YUI, TOSHIYA
Examiner	Art Unit
Mok, Alex W	2834

		SEARCHED		
Class		Subclass	Date	Examiner
310	239		4/24/2007	AM

SEARCH NOTES				
Search Note	es	Date	Examiner	
EAST		4/24/2007	AM	
PLUS		4/24/2007	AM	

Subclass	Date	Examiner
	Subclass	Subclass Date